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D. P. Attanayaka ; K. R. B. Herath

2017 8th National Conference on Technology and Management (NCTM)

Year: 2017

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IEEE Conferences

[Abstract](#) [HTML](#) (342 Kb)
☐ Modeling **Slump** of Concrete Using the Artificial Neural Networks

Wen-Huan Chine ; Li Chen ; Hsun-Hsin Hsu ; Tai-Sheng Wang ; Chang-Hung Chiu

2010 International Conference on Artificial Intelligence and Computational Intelligence

Year: 2010 , Volume: 3

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IEEE Conferences

[Abstract](#) [HTML](#) (311 Kb)
☐ V-band power amplifier MMICs exhibiting low power **slump** characteristics utilizing a production released 0.15-um GaAs PHEMT process

Charles F. Campbell ; Shabbir Moolchalla ; David Daugherty ; William J. Taft ; Ming-Yih Kao ; David Fanning

2009 IEEE MTT-S International Microwave Symposium Digest

Year: 2009

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☐ Effect of temperature on **slumping** behaviour of lead-free solder paste and its rheological simulation

A. E. Marks ; S. Malik ; N.N. Ekere ; A. Seman

2008 2nd Electronics System-Integration Technology Conference

Year: 2008

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☐ The case for contract manufacturing

R. Hassig

Proceedings of 1995 IEEE International **Test** Conference (ITC)

Year: 1995

Page : 296

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